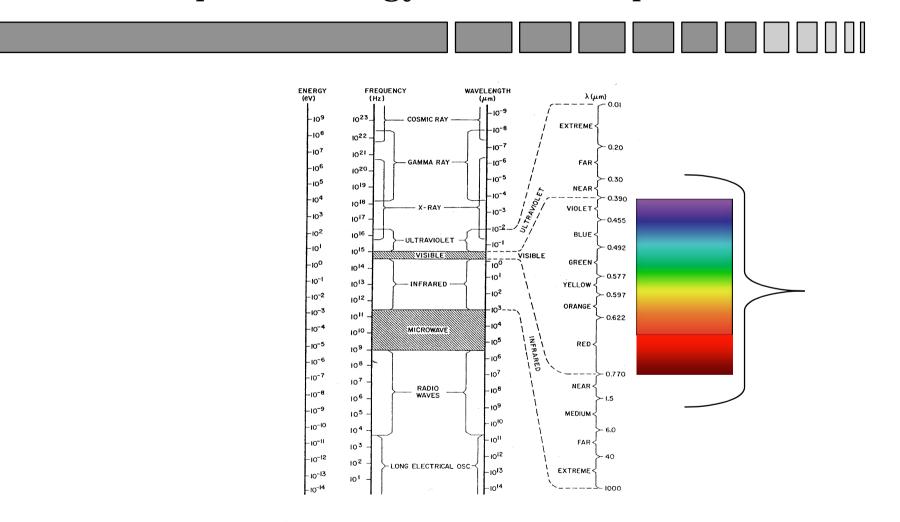
SENSORS and TRANSDUCERS

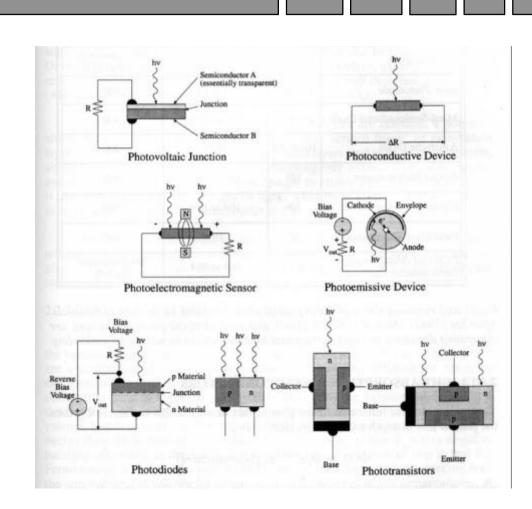
Klas Hjort, Materialvetenskap

- Microsensors in The Optical Energy Domain
 - Examples of microsensors in the optical energy domain
 - Semiconductor physics
 - Photodiodes
 - Phototransistors
 - Charge-coupled image sensors (CCDs)

Optical Energy Domain - Spectrum



Optical Energy Domain - Sensor Types



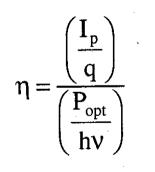
Optical Energy Domain - Definitions

Responsivity:

$$R_{I} = \frac{\text{output current}}{\text{optical input power}} = \frac{I_{p}}{P_{opt}} = \frac{\eta q}{h \nu} = \frac{\eta \lambda(\mu m)}{1.2398}$$

 $D^* \equiv \frac{\sqrt{A}}{NEP}$ in $\frac{cm\sqrt{Hz}}{W}$

where η is the quantum efficieny:

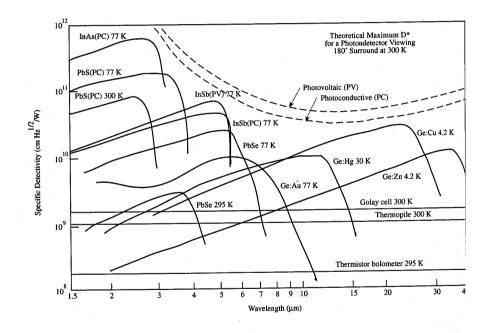


where the NEP is the noise equivalent power:

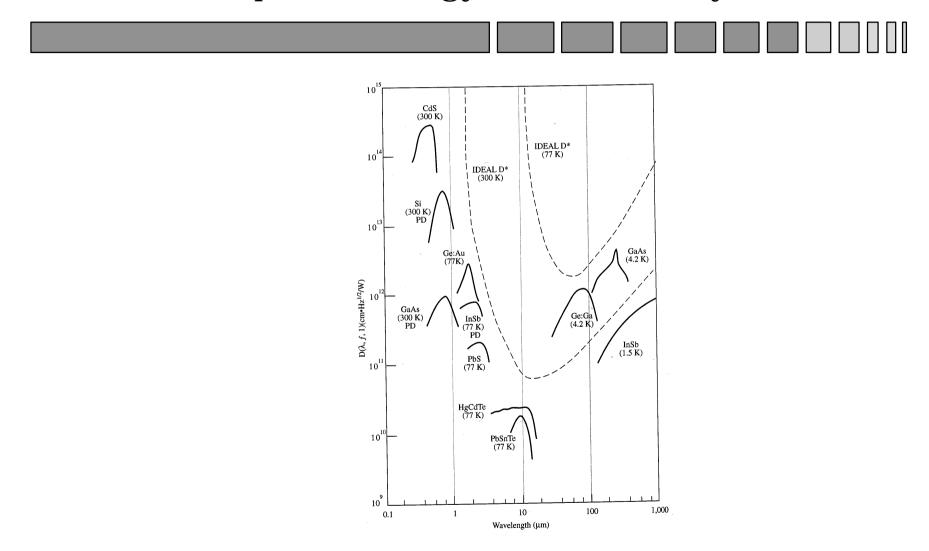
NEP =
$$\frac{\text{RMS noise current}\left(\frac{A}{\sqrt{\text{Hz}}}\right)}{R_{I}\left(\frac{A}{W}\right)}$$
 in $\left(\frac{W}{\sqrt{\text{Hz}}}\right)$

or, for a voltage-output device as,

NEP =
$$\frac{\text{RMS noise voltage}\left(\frac{V}{\sqrt{\text{Hz}}}\right)}{R_{V}\left(\frac{V}{W}\right)}$$
 in $\left(\frac{W}{\sqrt{\text{Hz}}}\right)$



Plots of detectivities of various detectors, including Golay cells, thermopiles, and bolometers for comparison. After Cobbold (1974). Photovoltaic and photoconduc tive devices are identified as "PC" and "PV," respectively.



- **†** Interaction of electromagnetic radiation with semiconductors
 - When a photon with energy $E_{ph} > hn = E_g$ coincides with a semiconductor an electron-hole pair is generated
 - The absorption is a function of temperature that can be described with

 $\Phi(x) = \mathbf{h} \cdot \Phi_0 \cdot \exp(-\mathbf{a} \cdot x)$

- where: η fraction of photons that coincide at the surface α absorption coefficient
- Bandgap distance
 - » Si 1.15 eV
 - » GaAs 1.43 eV

 Influence of tmperature and radiation on conductivity
In a *p*-*n* junction the number of electron-hole pairs per unit volume determines the conductivity S

The influence of temperature can be expressed in general as

$$S_T = q[n(T)m_n(T) + p(T)m_p(T)]$$
 where $S_T(\Omega^{-1}m^{-1})$

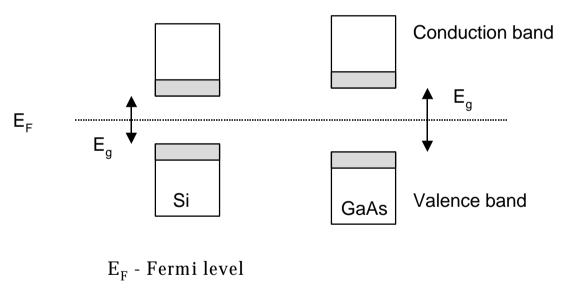
where: *n*, *p* - density of charge carriers

m- mobility of the charge carriers

The increase of conductivity due to the radiation can be expressed in general as

$$S_{I} = q [n(I)m_{n} + p(I)m_{p}]$$
$$S = S_{T} + S_{I}$$

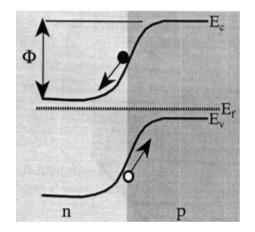
✤ Interaction of electromagnetic radiation with semiconductors



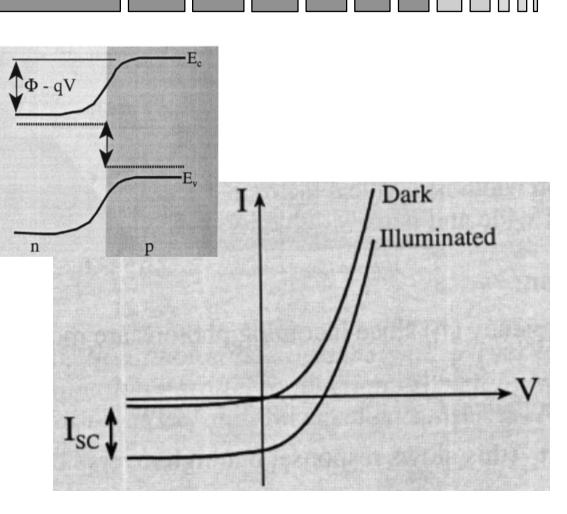
 E_g - bandgap distance (Si - 1.15 eV, GaAs - 1.43 eV)

Semiconductor	Bandgap (eV) 300 K	Bandgap (eV) 0 K	λ _{max} (μm) 300 K
BN	7.500	- "	0.165
С	5.470	5.480	0.227
ZnS	3.680	3.840	0.337
GaN	3.360	3.500	0.369
ZnO	3.350	3.420	0.370
Alpha-SiC	2.996	3.030	0.414
CdS	2.420	2.560	0.512
GaP	2.260	2.340	0.549
BP	2.000	-	0.620
CdSe	1.700	1.850	0.729
AlSb	1.580	1.680	0.785
CdTe	1.560	-	0.795
GaAs	1.420	1.520	0.873
InP	1.350	1.420	0.919
Si	1.120	1.170	1.107
GaSb	0.720	0.810	1.722
Ge	0.660	0.740	1.879
PbS	0.410	0.286	3.024
InAs	0.360	0.420	3.444
РbТе	0.310	0.190	4.000
InSb	0.170	0.230	7.294
Sn		0.082	15.122 @ 0 K

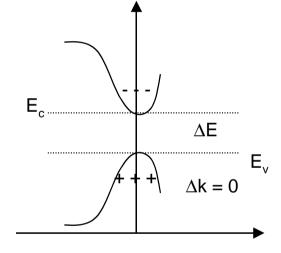
 $\Box \Pi$



Generation of a voltage at a pn-junction by creating an electron-hole pair

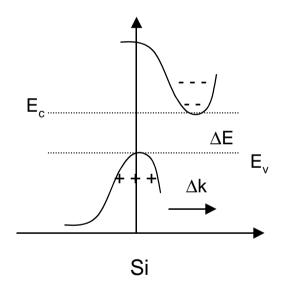






GaAs

Transition requires change in energy only



Transition requires change in energy and wave number

† Direct- and indirect- bandgap materials

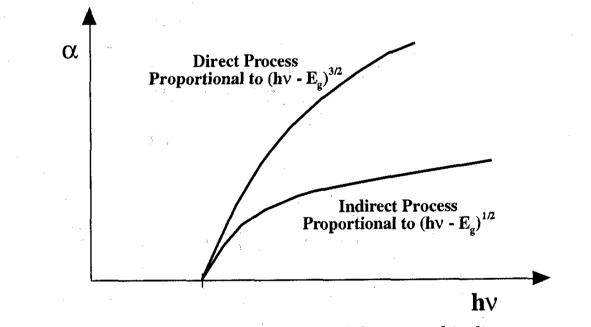
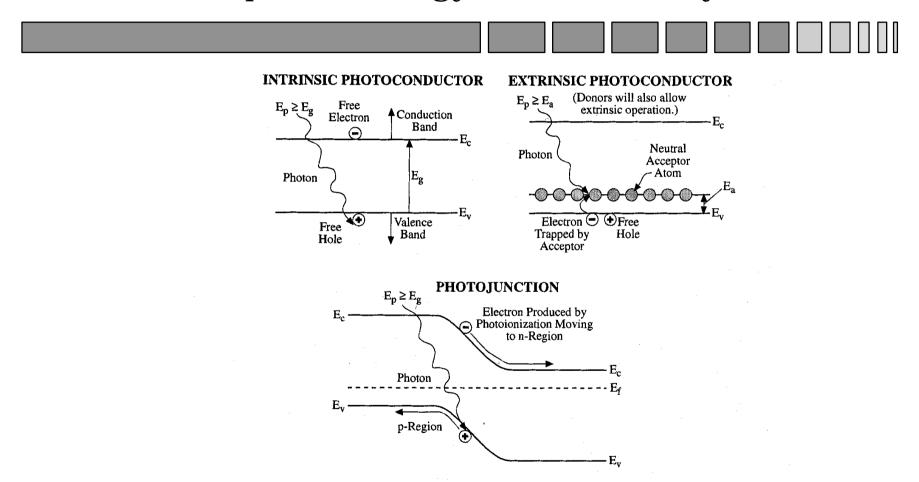
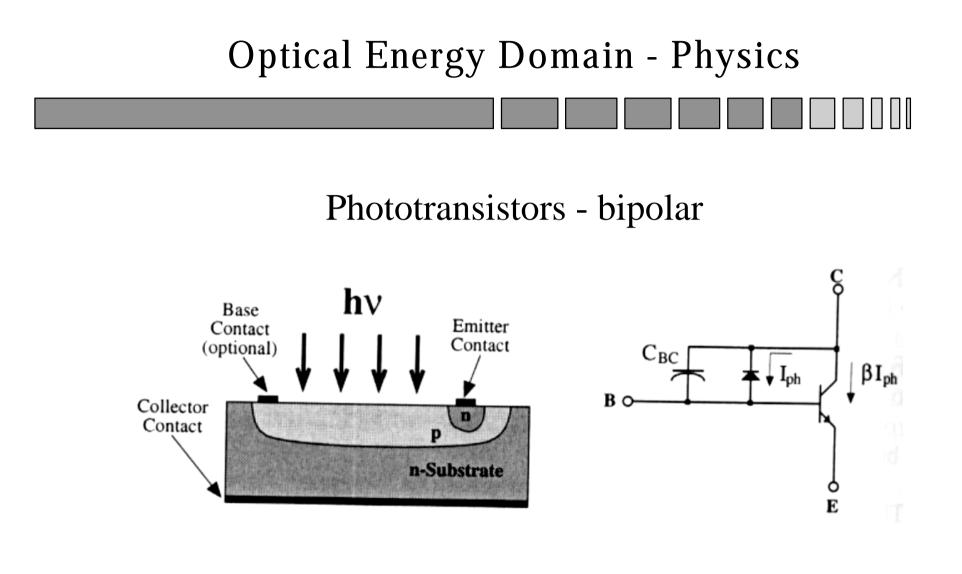


Illustration of the absorption spectra of direct and indirect processes.



Comparative band diagrams for intrinsic-, extrinsic- and photojunction-type optical sensors. After Cobbold (1974).



Charge-coupled image sensors (CCD)

